

IRHLS87Y50

PD-97956B

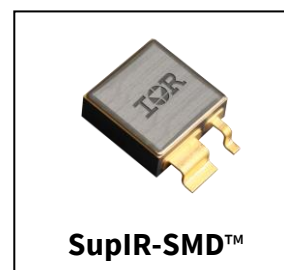
Radiation Hardened Logic Power MOSFET Surface-Mount (SupIR-SMD™) 20V, 75A, N-channel, R8 Technology

Features

- Single event effect (SEE) hardened (up to LET of 92 MeV·cm²/mg)
- 5V CMOS and TTL compatible
- Low R_{DS(on)}
- Fast switching
- Low total gate charge
- Simple drive requirements
- Hermetically sealed
- Surface mount
- Light weight
- ESD rating: class 2 per MIL-STD-750, Method 1020

Product Summary

- **BV_{DSS}**: 20V
- **I_D**: 75A*
- **R_{DS(on), max}**: 2.5mΩ
- **Q_{G, max}**: 130nC



Potential Applications

- Point-of-Load (PoL) converters for FPGA, ASIC and DSP core rails
- Synchronous rectification
- Redundant power distribution

Product Validation

Qualified according to MIL-PRF-19500 for space applications

Description

IR HiRel R8 Logic level power MOSFETs provide simple solution to interfacing CMOS and TTL control circuits to power devices in space and other radiation environments. The threshold voltage remains within acceptable operating limits over the full operating temperature and post radiation. This is achieved while maintaining single event gate rupture and single event burnout immunity. The device is ideal when used to interface directly with most logic gates, linear IC's, micro-controllers, and other device types that operate from a 3.3-5V source. It may also be used to increase the output current of a PWM, voltage comparator or an operational amplifier where the logic level drive signal is available.

Ordering Information

Table 1 **Ordering options**

Part number	Package	Screening Level	TID Level
IRHLS87Y50	SupIR-SMD™	COTS	100krad(Si)
IRHLS87Y50SCS	SupIR-SMD™	QIRL	100krad(Si)

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Absolute Maximum Ratings

1 Absolute Maximum Ratings

Table 2 Absolute Maximum Ratings (Pre-Irradiation)

Symbol	Parameter	Value	Unit
$I_{D1} @ V_{GS} = 4.5V, T_C = 25^{\circ}C$	Continuous Drain Current	75*	A
$I_{D2} @ V_{GS} = 4.5V, T_C = 100^{\circ}C$	Continuous Drain Current	75*	A
$I_{DM} @ T_C = 25^{\circ}C$	Pulsed Drain Current ¹	300	A
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	125	W
	Linear Derating Factor	1.0	W/°C
V_{GS}	Gate-to-Source Voltage	+ 12/-10	V
E_{AS}	Single Pulse Avalanche Energy ²	535	mJ
I_{AR}	Avalanche Current ¹	75	A
E_{AR}	Repetitive Avalanche Energy ¹	12.5	mJ
dv/dt	Peak Diode Reverse Recovery ³	0.8	V/ns
T_J T_{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C
	Lead Temperature	300 (for 5s)	
	Weight	3.3 (Typical)	

* Current is limited by package

¹ Repetitive Rating; Pulse width limited by maximum junction temperature.² $V_{DD} = 20V$, starting $T_J = 25^{\circ}C$, $L = 0.19mH$, Peak $I_L = 75A$, $V_{GS} = 10V$ ³ $I_{SD} \leq 75A$, $di/dt \leq 450A/\mu s$, $V_{DD} \leq 20V$, $T_J \leq 150^{\circ}C$

Device Characteristics

2 Device Characteristics

2.1 Electrical Characteristics (Pre-Irradiation)

Table 3 Static and Dynamic Electrical Characteristics @ $T_j = 25^\circ\text{C}$ (Unless Otherwise Specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	20	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.02	—	V/ $^\circ\text{C}$	Reference to 25°C , $I_D = 250\mu A$
$R_{DS(on)}$	Static Drain-to-Source On-State Resistance	—	—	2.5	$m\Omega$	$V_{GS} = 4.5V, I_{D2} = 75A^1$
		—	—	2.3		$V_{GS} = 7.0V, I_{D2} = 75A^1$
$V_{GS(th)}$	Gate Threshold Voltage	1.0	—	2.3	V	$V_{DS} \geq V_{GS}, I_D = 1.8mA$
$\Delta V_{GS(th)}/\Delta T_J$	Gate Threshold Voltage Coefficient	—	-4.3	—	mV/ $^\circ\text{C}$	
G_{fs}	Forward Transconductance	75	—	—	S	$V_{DS} = 15V, I_{D2} = 75A^1$
I_{DSS}	Zero Gate Voltage Drain Current	—	—	1.0	μA	$V_{DS} = 16V, V_{GS} = 0V$
		—	—	50		$V_{DS} = 16V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
I_{GSS}	Gate-to-Source Leakage Forward	—	—	100	nA	$V_{GS} = 12V$
	Gate-to-Source Leakage Reverse	—	—	-100		$V_{GS} = -10V$
Q_G	Total Gate Charge	—	—	130	nC	$I_{D1} = 75A$ $V_{DS} = 10V$ $V_{GS} = 4.5V$
Q_{GS}	Gate-to-Source Charge	—	—	50		
Q_{GD}	Gate-to-Drain ('Miller') Charge	—	—	35		
$t_{d(on)}$	Turn-On Delay Time	—	—	80	ns	$I_{D1} = 75A^{**}$ $V_{DD} = 10V$ $R_G = 2.35\Omega$ $V_{GS} = 4.5V$
t_r	Rise Time	—	—	130		
$t_{d(off)}$	Turn-Off Delay Time	—	—	100		
t_f	Fall Time	—	—	55		
$L_S + L_D$	Total Inductance	—	12	—	nH	Measured from center of Drain pad to center of Source pad
C_{iss}	Input Capacitance	—	15330	—	pF	$V_{GS} = 0V$ $V_{DS} = 20V$ $f = 1.0MHz$
C_{oss}	Output Capacitance	—	3140	—		
C_{rss}	Reverse Transfer Capacitance	—	610	—		
R_G	Gate Resistance	—	0.4	—	Ω	$f = 1.0MHz$, open drain

** Switching speed maximum limits are based on manufacturing test equipment and capability.

¹ Pulse width $\leq 400\mu s$; Duty Cycle $\leq 2\%$

Device Characteristics

2.2 Source-Drain Diode Ratings and Characteristics (Pre-Irradiation)

Table 4 Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
I _S	Continuous Source Current (Body Diode)	—	—	75	A	
I _{SM}	Pulsed Source Current (Body Diode) ¹	—	—	300	A	
V _{SD}	Diode Forward Voltage	—	—	1.0	V	T _J = 25°C, I _S = 75A, V _{GS} = 0V ²
t _{rr}	Reverse Recovery Time	—	—	100	ns	T _J = 25°C, I _F = 75A, V _{DD} ≤ 20V di/dt = -100A/μs
Q _{rr}	Reverse Recovery Charge	—	143	—	nC	
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)				

2.3 Thermal Characteristics

Table 5 Thermal Resistance

Symbol	Parameter	Min.	Typ.	Max.	Unit
$R_{\theta JC}$	Junction-to-Case	—	—	1.0	$^\circ\text{C}/\text{W}$

2.4 Radiation Characteristics

IR HiRel radiation hardened MOSFETs are tested to verify their radiation hardness capability. The hardness assurance program at IR HiRel is comprised of two radiation environments. Every manufacturing lot is tested for total ionizing dose (per notes 3 and 4) using the TO-3 package. Both pre- and post-irradiation performance are tested and specified using the same drive circuitry and test conditions in order to provide a direct comparison.

2.4.1 Electrical Characteristics - Post Total Dose Irradiation

Table 6 Electrical Characteristics @ $T_J = 25^\circ\text{C}$, Post Total Dose Irradiation^{3, 4}

Symbol	Parameter	Up to 100krads (Si) ⁵		Unit	Test Conditions
		Min.	Max.		
BV_{DSS}	Drain-to-Source Breakdown Voltage	20	—	V	$V_{GS} = 0\text{V}$, $I_D = 1\text{mA}$
$V_{GS(th)}$	Gate Threshold Voltage	1.0	2.3	V	$V_{DS} \geq V_{GS}$, $I_D = 1.8\text{mA}$
I_{GSS}	Gate-to-Source Leakage Forward	—	100	nA	$V_{GS} = 12\text{V}$
	Gate-to-Source Leakage Reverse	—	-100		$V_{GS} = -10\text{V}$
I_{DSS}	Zero Gate Voltage Drain Current	—	1.0	μA	$V_{DS} = 16\text{V}$, $V_{GS} = 0\text{V}$
$R_{DS(on)}$	Static Drain-to-Source On-State Resistance (TO-3) ²	—	3.0	$\text{m}\Omega$	$V_{GS} = 4.5\text{V}$, $I_{D2} = 75\text{A}$
$R_{DS(on)}$	Static Drain-to-Source On-State Resistance (SupIR-SMD) ²	—	2.5	$\text{m}\Omega$	$V_{GS} = 4.5\text{V}$, $I_{D2} = 75\text{A}$
V_{SD}	Diode Forward Voltage ²	—	1.0	V	$V_{GS} = 0\text{V}$, $I_F = 75\text{A}$

¹ Repetitive Rating; Pulse width limited by maximum junction temperature.² Pulse width $\leq 400\mu\text{s}$; Duty Cycle $\leq 2\%$ ³ Total Dose Irradiation with V_{GS} Bias. $V_{GS} = 12\text{V}$ applied and $V_{DS} = 0$ during irradiation per MIL-STD-750, Method 1019, condition A.⁴ Total Dose Irradiation with V_{DS} Bias. $V_{DS} = 16\text{V}$ applied and $V_{GS} = 0$ during irradiation per MIL-STD-750, Method 1019, condition A.

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Radiation Hardened Logic Power MOSFET (SupIR-SMD™)

Device Characteristics

2.4.2 Single Event Effects – Safe Operating Area

IR HiRel radiation hardened MOSFETs have been characterized in heavy ion environment for Single Event Effects (SEE). Single Event Effects characterization is illustrated in Fig. 1 and Table 7.

Table 7 Typical Single Event Effects Safe Operating Area

LET (MeV·cm ² /mg)	Energy (MeV)	Range (μm)	V _{DS} (V)		
			V _{GS} = 0V	V _{GS} = -1V	V _{GS} = -2V
40 ± 5%	275 ± 5%	35.6 ± 5%	16	16	—
64 ± 7.5%	600 ± 12.5%	49 ± 10%	14	14	—
92 ± 5%	1150 ± 5%	65.1 ± 5%	12	12	—

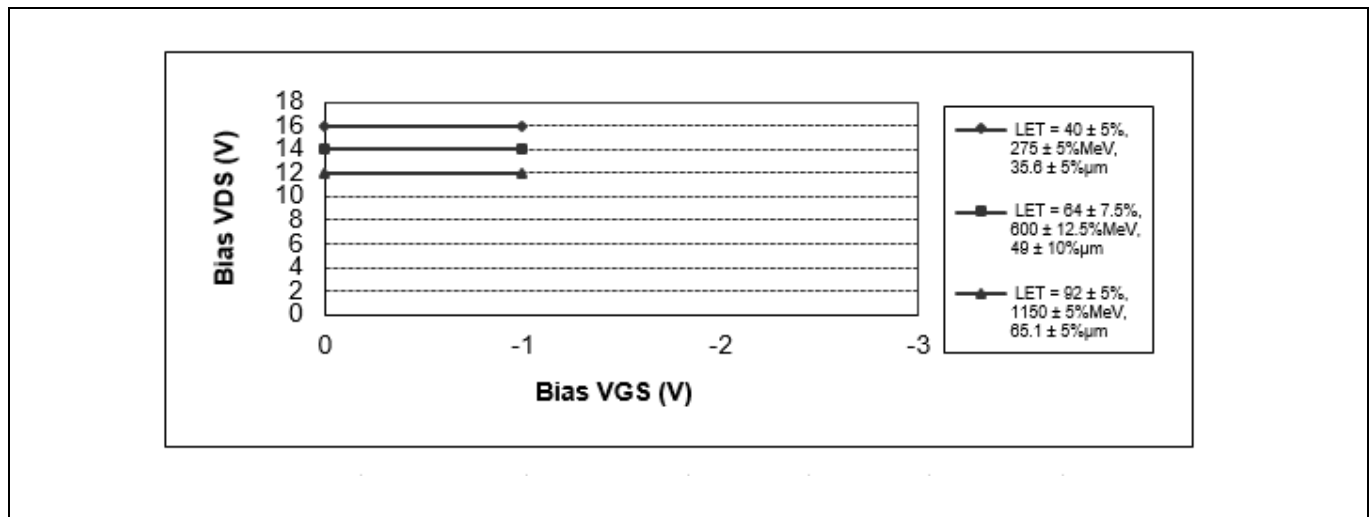


Figure 1 Typical Single Event Effect, Safe Operating Area

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Radiation Hardened Logic Power MOSFET (SupIR-SMD™)

Electrical Characteristics Curves (Pre-irradiation)

3 Electrical Characteristics Curves (Pre-irradiation)

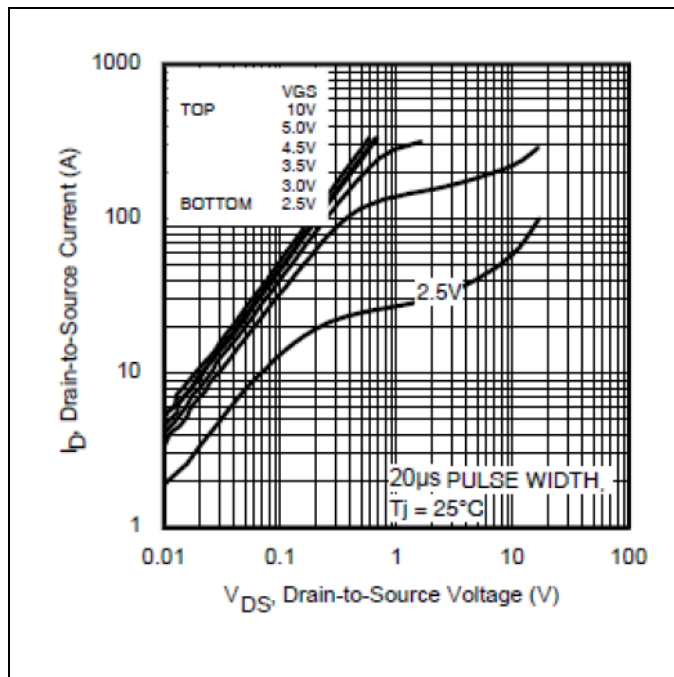


Figure 2 Typical Output Characteristics

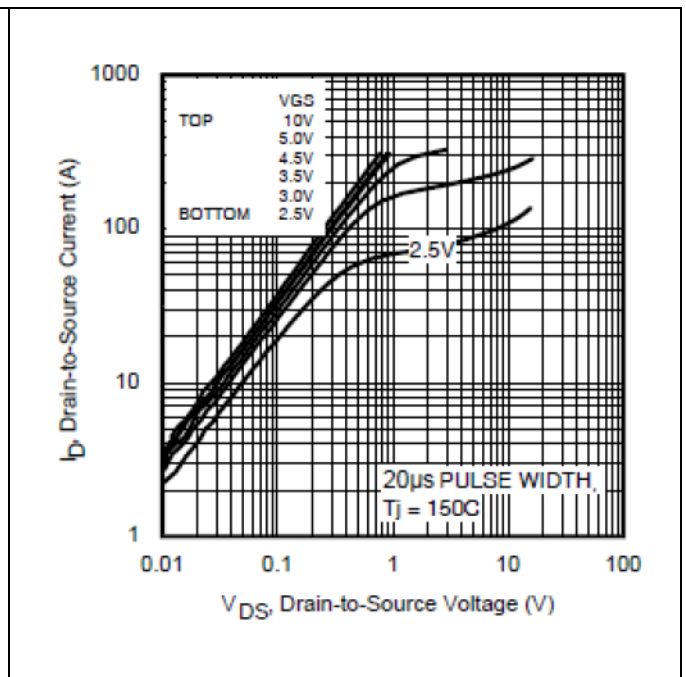


Figure 3 Typical Output Characteristics

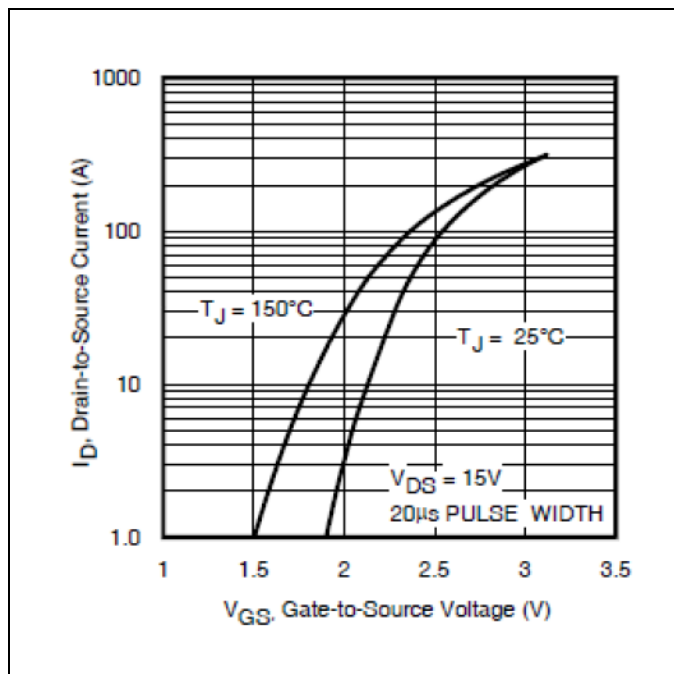


Figure 4 Typical Transfer Characteristics

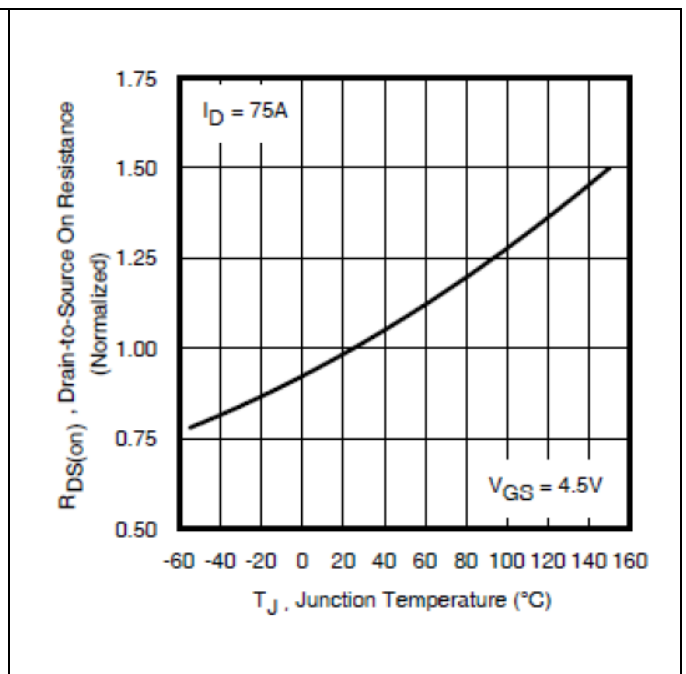


Figure 5 Normalized On-Resistance Vs. Temperature

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Radiation Hardened Logic Power MOSFET (SupIR-SMD™)

Electrical Characteristics Curves (Pre-irradiation)

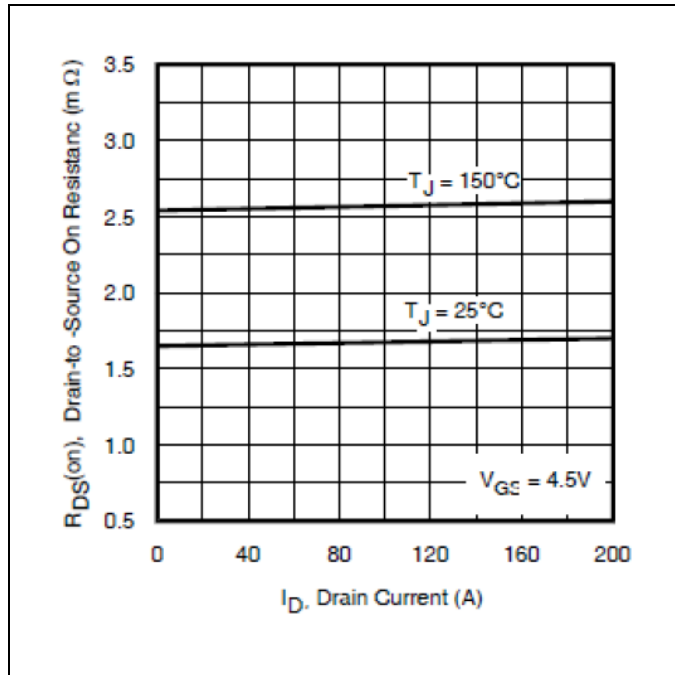


Figure 6 Typical On-Resistance Vs. Gate Voltage

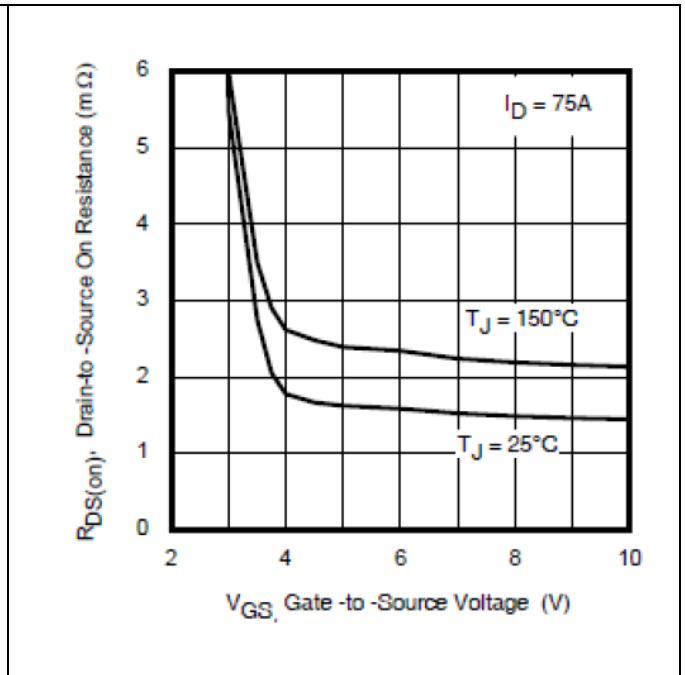


Figure 7 Typical On-Resistance Vs. Drain Current

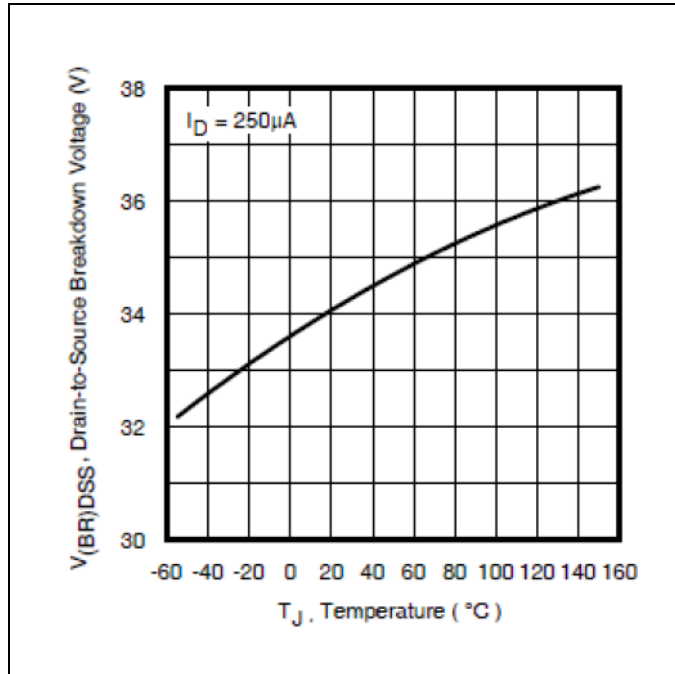


Figure 8 Typical Drain-to-Source Breakdown Voltage Vs. Temperature

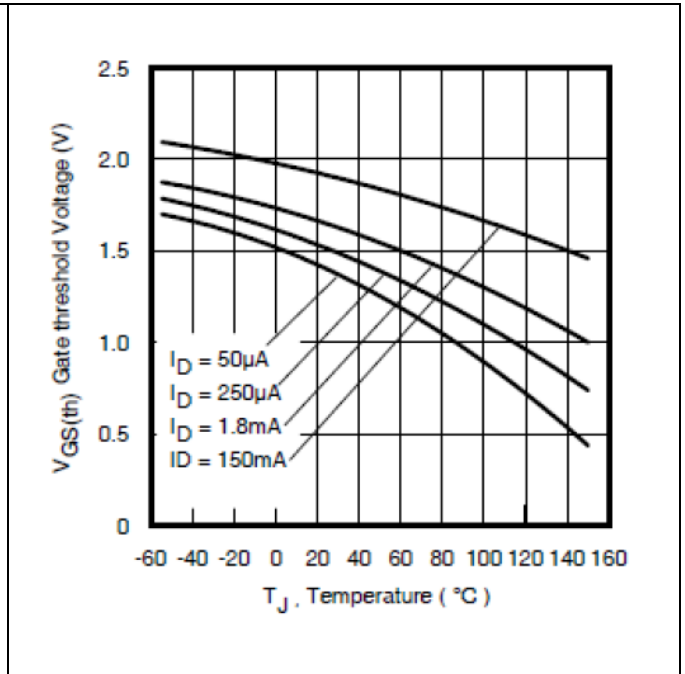


Figure 9 Typical Threshold Voltage Vs. Temperature

Electrical Characteristics Curves (Pre-irradiation)

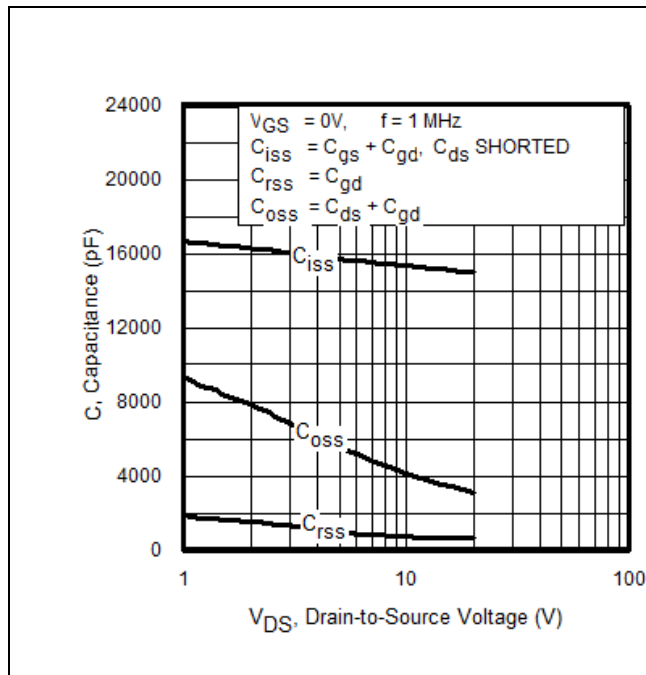


Figure 10 Typical Capacitance Vs. Drain-to-Source Voltage

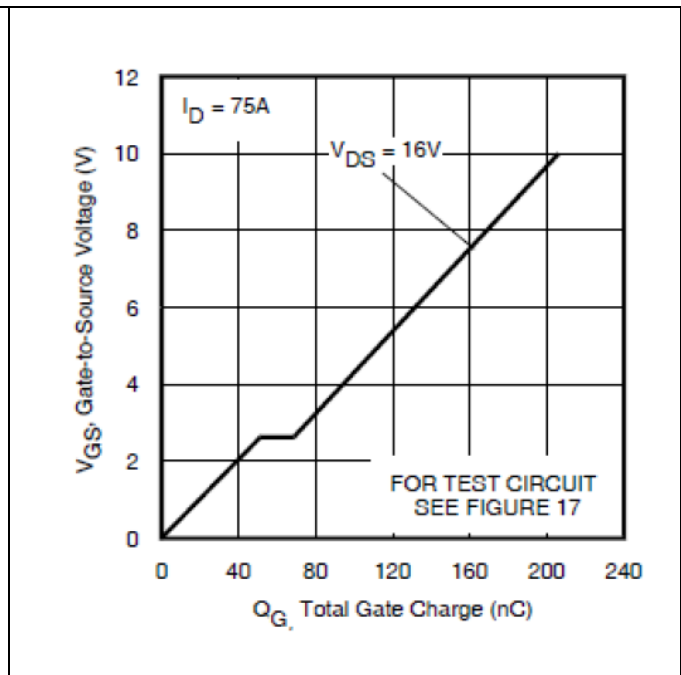


Figure 11 Typical Gate Charge Vs. Gate-to-Source Voltage

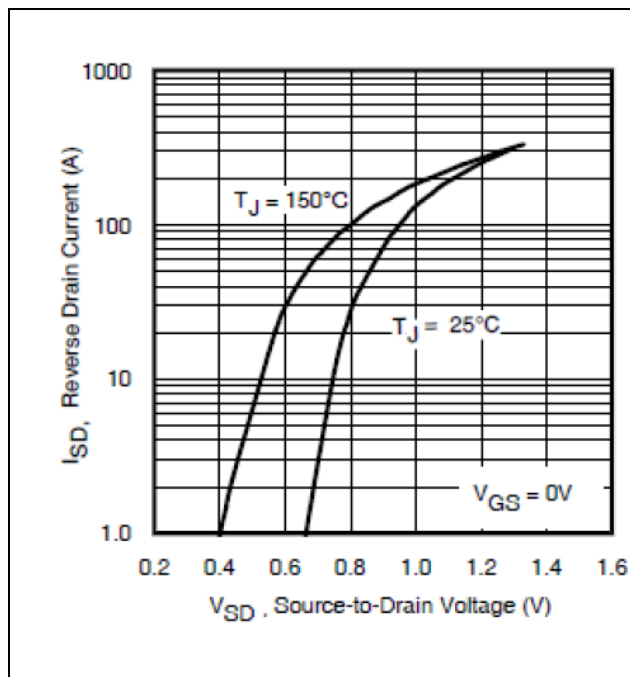


Figure 12 Typical Source-Drain Vs. Diode Forward Voltage

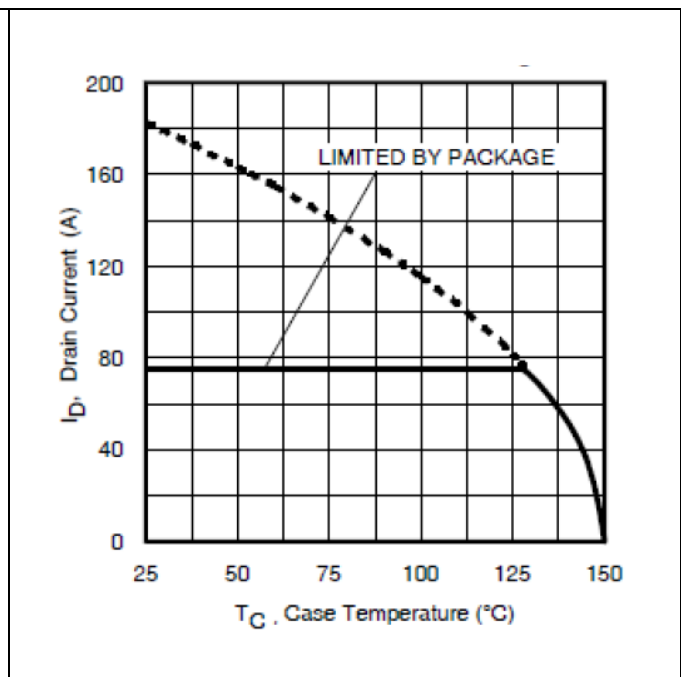


Figure 13 Maximum Drain Current Vs. Case Temperature

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Radiation Hardened Logic Power MOSFET (SupIR-SMD™)

Electrical Characteristics Curves (Pre-irradiation)

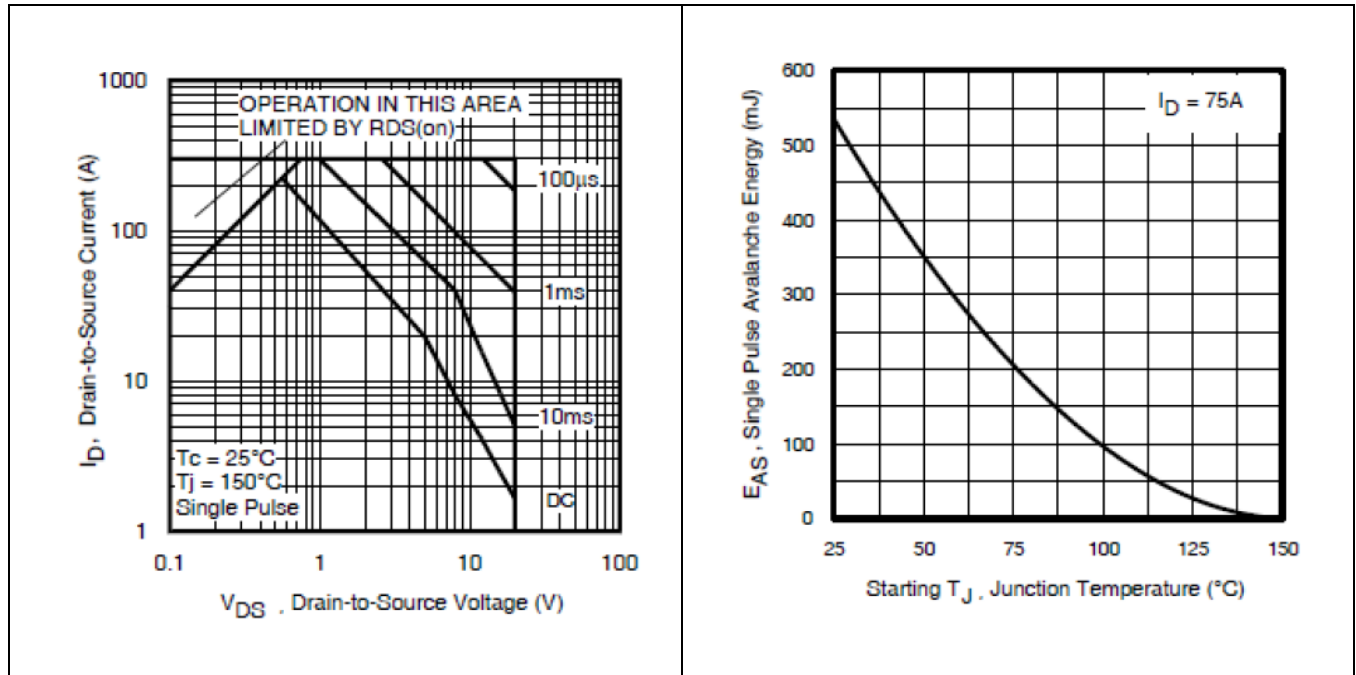


Figure 14 Maximum Safe Operating Area

Figure 15 Maximum Avalanche Energy Vs. Drain Current

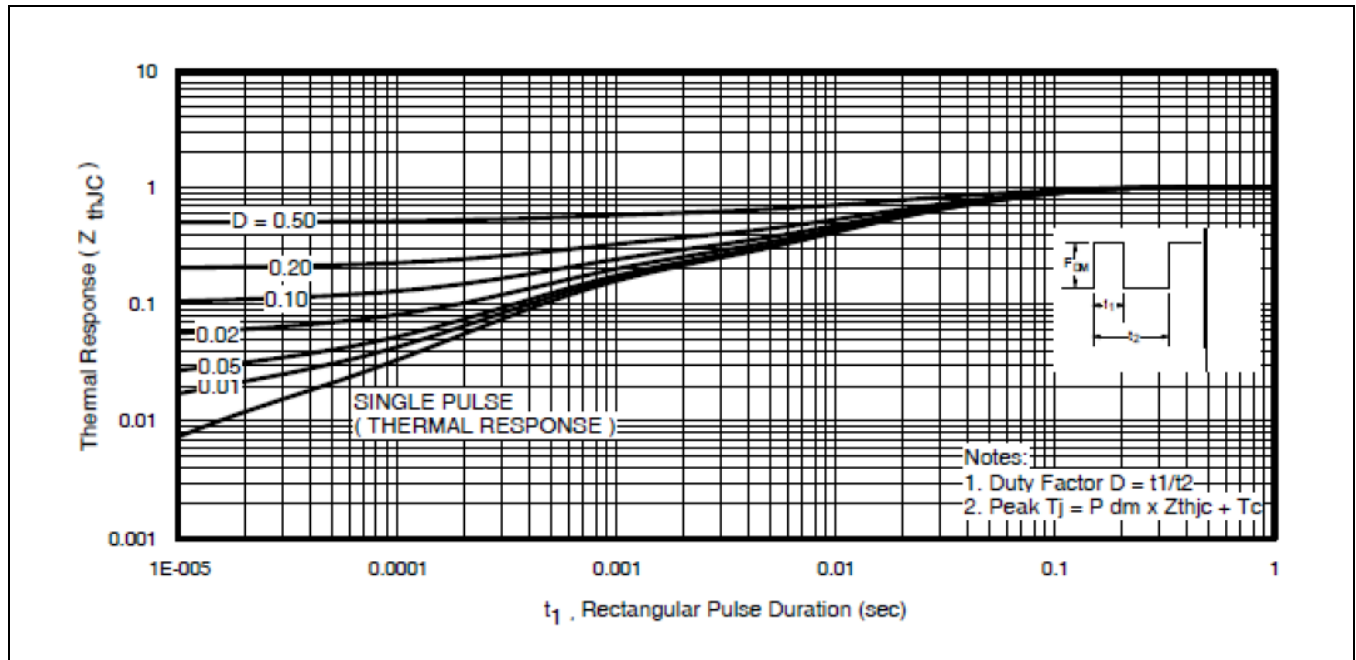


Figure 16 Maximum Effective Transient Thermal Impedance, Junction-to-Case

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Radiation Hardened Logic Power MOSFET (SupIR-SMD™)

Test Circuits (Pre-irradiation)

4 Test Circuits (Pre-irradiation)

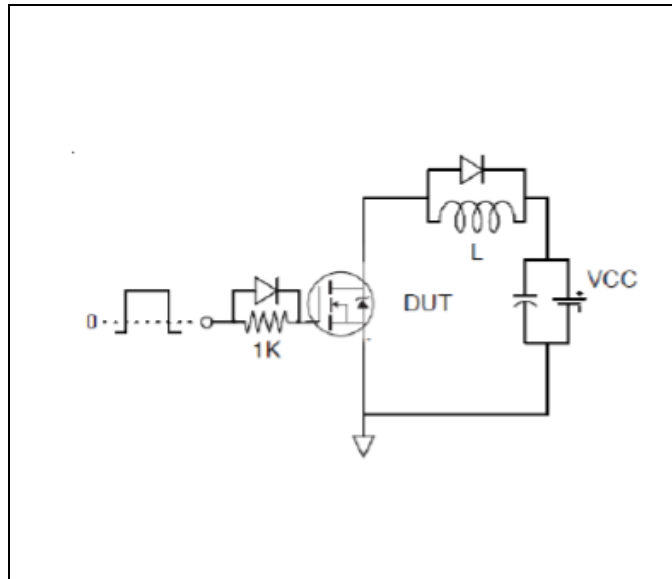


Figure 17 Gate Charge Test Circuit

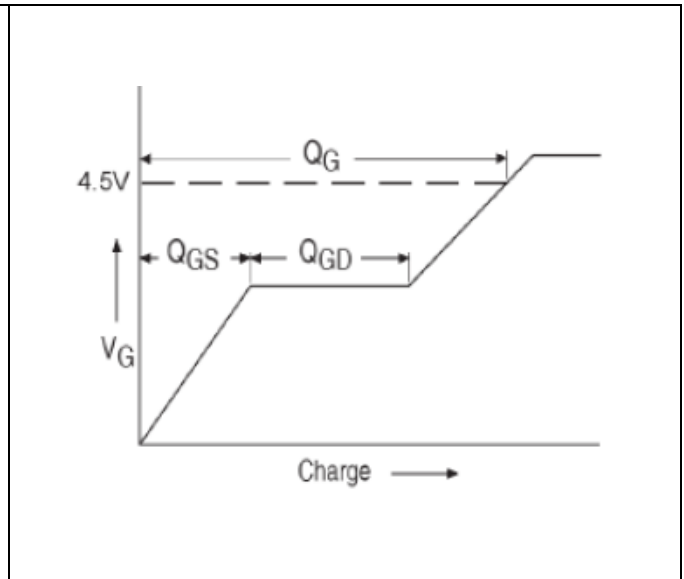


Figure 18 Gate Charge Waveform

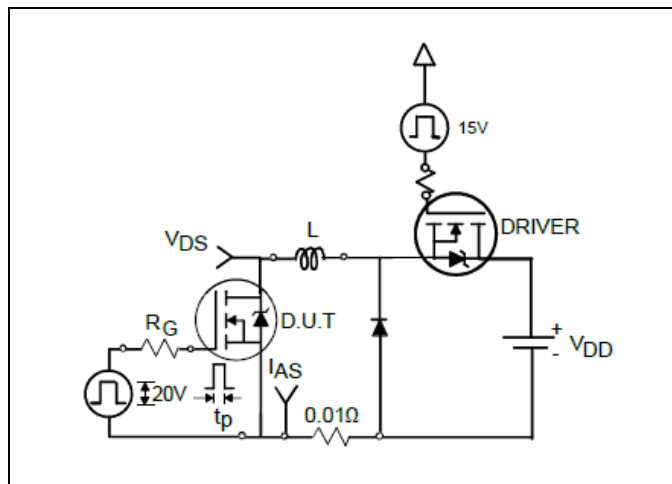


Figure 19 Unclamped Inductive Test Circuit

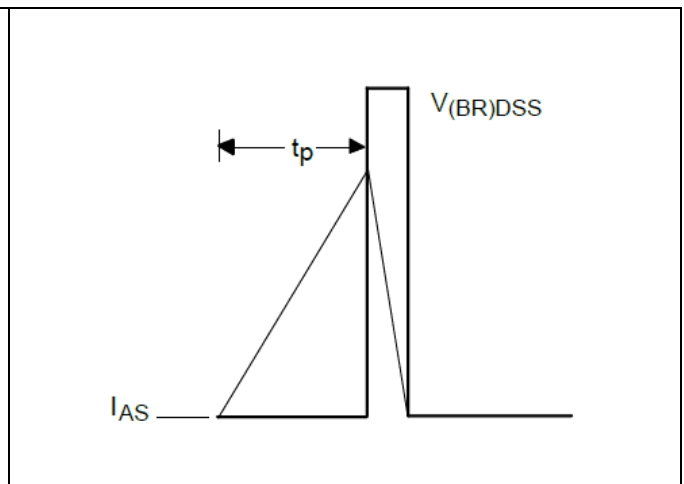


Figure 20 Unclamped Inductive Waveform

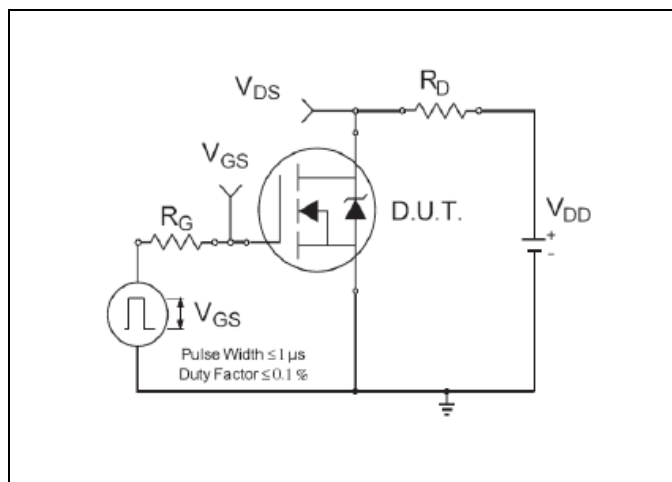


Figure 21 Switching Time Test Circuit

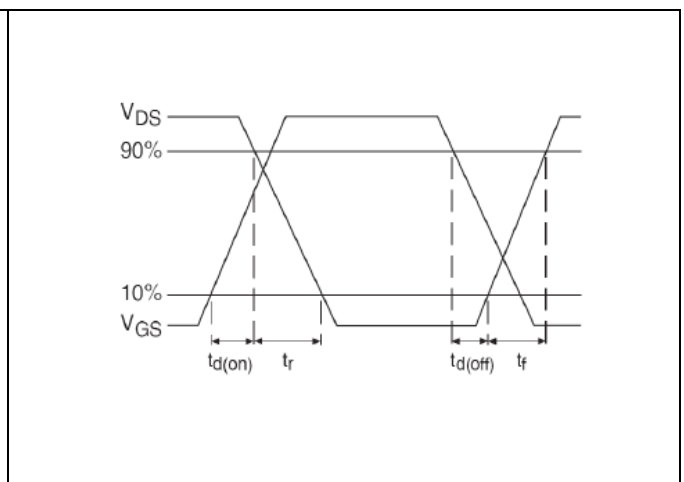
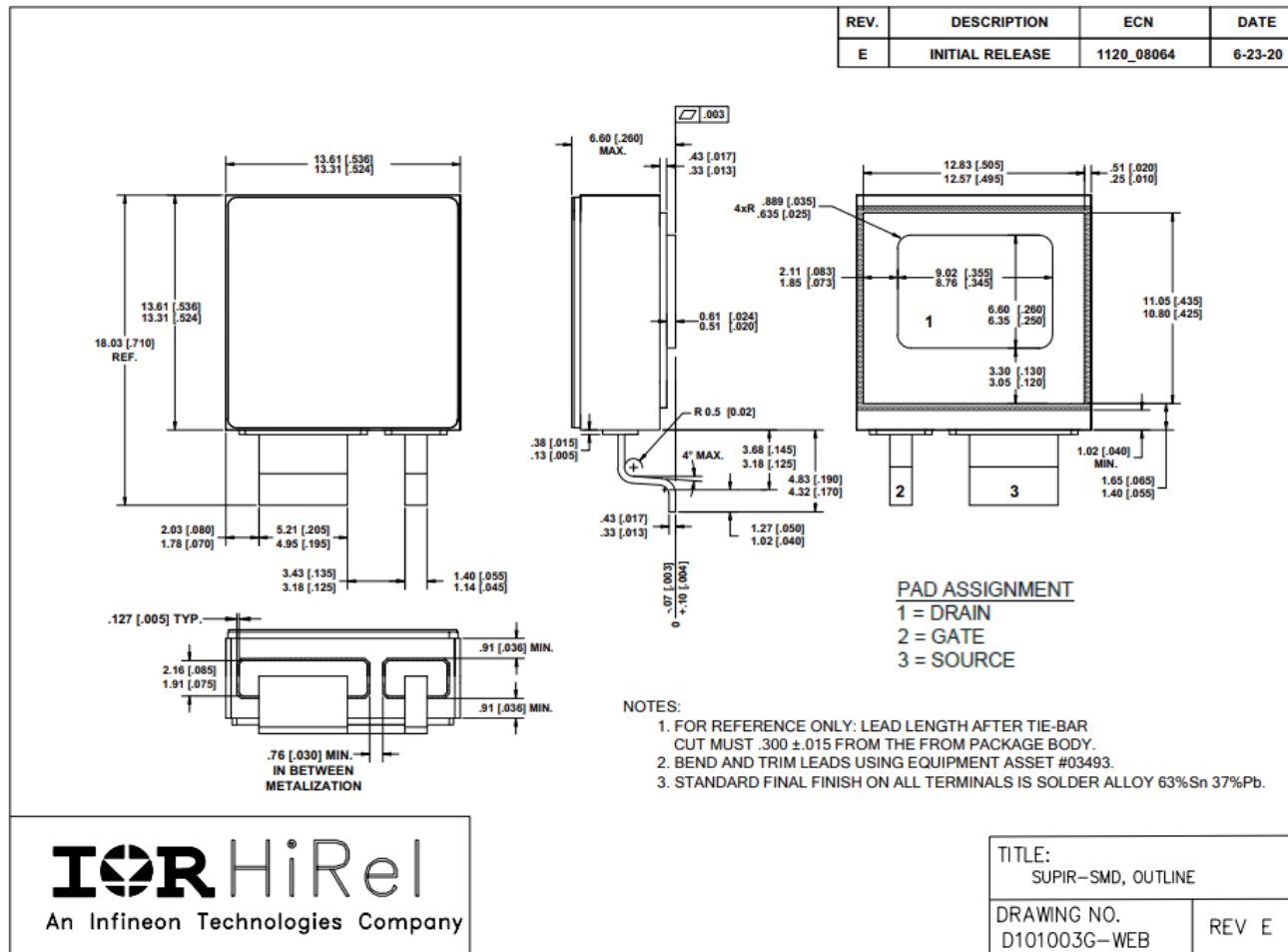


Figure 22 Switching Time Waveforms

Package Outline

5 Package Outline

Note: For the most updated package outline, please see the website: [SupIR-SMD](https://www.infineon.com/products/radiation-hardened/supir-smd)



Revision history**Revision history**

Document version	Date of release	Description of changes
	03/22/2021	Final datasheet with PD number (PD-97956)
Rev A	01/31/2022	Updated based on ECN-1120_08881
Rev B	11/04/2022	Updated based on ECN-1120_09312

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